Power MOSFET

40 V, 1.15 m Ω , 252 A, Single N-Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	40	V
Gate-to-Source Voltage			V_{GS}	±20	٧
Continuous Drain	Steady T _C = 25°C		I _D	252	Α
Current R _{θJC} (Notes 1, 3)	State	T _C = 100°C		178	
Power Dissipation		T _C = 25°C	P_{D}	134	W
R _{θJC} (Note 1)		T _C = 100°C		67	
Continuous Drain	Steady State	T _A = 25°C	I _D	43	Α
Current R _{0JA} (Notes 1, 2, 3)	State	T _A = 100°C		30	
Power Dissipation	T _A = 25°C		P_{D}	3.9	W
R _{θJA} (Notes 1, 2)		T _A = 100°C		1.9	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	900	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to + 175	°C
Source Current (Body Diode)			Is	112	Α
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 21 A)			E _{AS}	1621	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.12	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

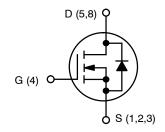
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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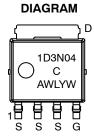
V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40 V	1.15 mΩ @ 10 V	252 A



N-CHANNEL MOSFET



LFPAK4 CASE 760AB



MARKING

1D3N04C = Specific Device Code A = Assembly Location

WL = Wafer Lot
 Y = Year
 W = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•	•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				20		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V. T _J = 25°C				10	
		$V_{GS} = 0 \text{ V},$ $V_{DS} = 40 \text{ V}$	T _J = 125°C			100	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 180 μΑ	2.5		3.5	V
Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-8.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 50 A		0.96	1.15	mΩ
Forward Transconductance	9FS	V_{DS} =15 V, I_{D}	= 50 A		143		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C _{ISS}				4855		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz	z, V _{DS} = 25 V		2565		pF
Reverse Transfer Capacitance	C _{RSS}				71		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 32 V; I _D = 50 A			75		
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 10 V, V _{DS} = 32 V; I _D = 50 A			12		0
Gate-to-Source Charge	Q _{GS}				20		nC
Gate-to-Drain Charge	Q_{GD}				17		1
Plateau Voltage	V _{GP}				4.4		V
SWITCHING CHARACTERISTICS (Note 5	5)						
Turn-On Delay Time	t _{d(ON)}				15		
Rise Time	t _r	$V_{GS} = 10 \text{ V}, V_{DS}$	s = 32 V,		22		
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 50 \text{ A}, R_G = 2.5 \Omega$			48		ns -
Fall Time	t _f				16		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C		0.8	1.2	
		T _J = 125°C		0.6		V	
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			70		
Charge Time	ta				40		ns
Discharge Time	t _b				30		1
Reverse Recovery Charge	Q _{RR}				105		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

^{5.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

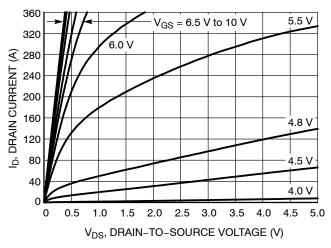


Figure 1. On-Region Characteristics

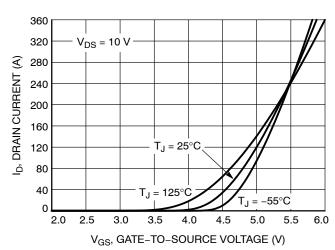


Figure 2. Transfer Characteristics

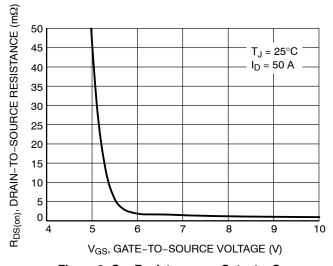


Figure 3. On-Resistance vs. Gate-to-Source Voltage

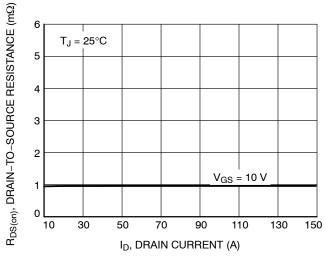


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

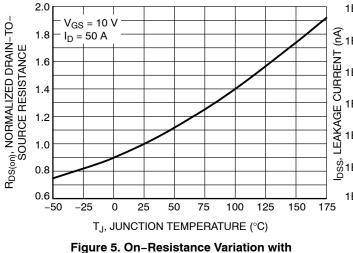


Figure 5. On–Resistance variation with Temperature

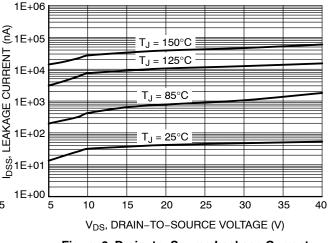


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

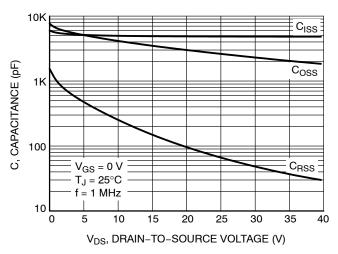


Figure 7. Capacitance Variation

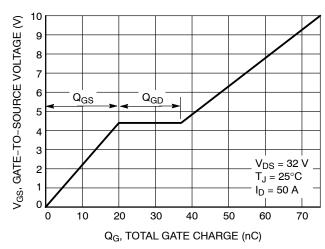


Figure 8. Gate-to-Source Voltage vs. Total Charge

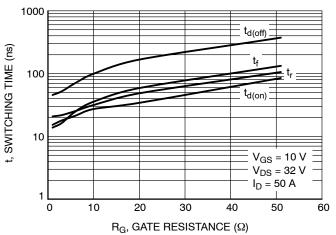


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

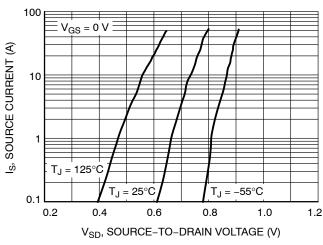


Figure 10. Diode Forward Voltage vs. Current

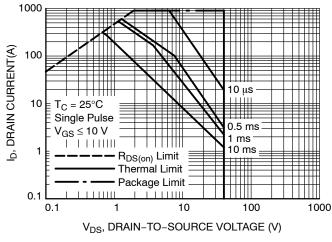


Figure 11. Maximum Rated Forward Biased Safe Operating Area

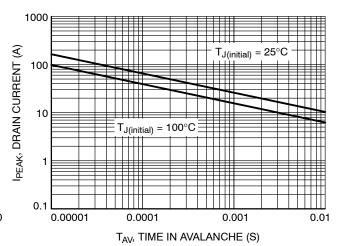


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

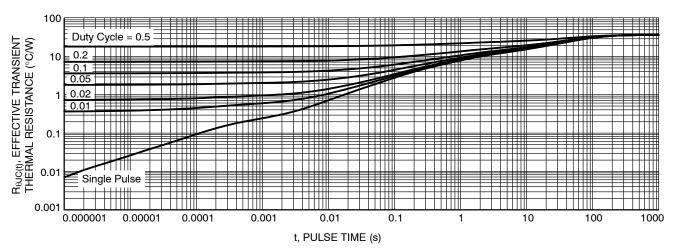


Figure 13. Thermal Response

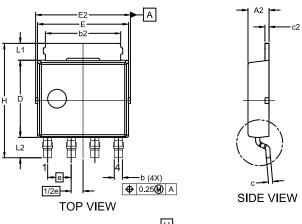
DEVICE ORDERING INFORMATION

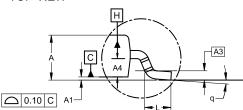
Device	Marking	Package	Shipping [†]
NVMYS1D3N04CTWG	1D3N04C	LFPAK4 (Pb-Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

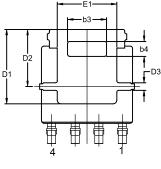
PACKAGE DIMENSIONS

LFPAK4 5x6 CASE 760AB ISSUE O

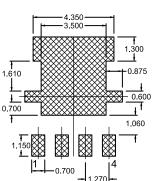












RECOMMENDED MOUNTING FOOTPRINT

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

LINIT IN MILLIMETED					
UNIT IN MILLIMETER					
DIM	MIN	NOM	MAX		
Α	1.10	1.20	1.30		
A1	0.00	0.08	0.15		
A2	1.10	1.15	1.20		
А3		0.25			
A4	0.45	0.50	0.55		
b	0.40	0.45	0.50		
b2	3.80	4.10	4.40		
b3	2.00	2.10	2.20		
b4	0.70	0.80	0.90		
С	0.19	0.22	0.25		
c2	0.19	0.22	0.25		
D	4.05	4.15	4.25		
D1	-	-	4.20		
D2	3.0	3.10	3.20		
D3	0.30	0.40	0.50		
Е	4.80	4.90	5.00		
E1	3.10	3.20	3.30		
E2	5.00	5.15	5.30		
е	1.27 BSC				
Н	6.00	6.15	6.30		
L	0.40	0.65	0.85		
L1	0.80	0.90	1.00		
L2	0.80	1.05	1.30		
q	0°	4°	8°		

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